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| | Degrees: B.S.E., Duke University |
| | M.S., University of Rochester |
| 20 | Ph.D., University of Rochester (2013) |
| | Research Interests |
| | Analysis, modeling, and design methodologies for high performance digital and mixed-signal integrated circuits; Emerging integrated circuit technologies; Electrical and thermal modeling and characterization, signal and |
| | power integrity, and power and clock delivery for 3-D IC technologies; hardware security (obfuscation and side-channel analysis); algorithms and methodologies for design automation including ML/AI based |
| | optimization; On-chip power management; Low-power circuit techniques; Algorithms and methodologies for |
| | secure IC design |
| | LABORATORY & TEAM |
| | - Seven Ph.D. students |
| | Alec Aversa – Sequential digital circuit obfuscation |
| | - Vaibhav Venugopal Rao – Analog IC IP protection |
| | - Saran Phatharodom – Digital obfuscation metrics |
| | - Jeff Wu – Application of ML/AI to analog IC design |
| | - Ziyi Chen – Analog IP protection |
| | - Ashish Sharma – Heterogeneous circuit integration |
| | Pratik Shrestha – Digital security and application of ML/AI to digital IC design |
| | - One B.S. student |
| | Isabel Song (UPenn undergraduate) – ML/AI analog IC design |
| | - 2,000 square feet of dedicated research space |
| of Drevel | Access to leading CAD software packages: Cadence (Virtuoso, Encounter, assure), |
| UNIVERSITY | Synopsys (Primetime, Hspice, Taurus), and Siemens Mentor Graphics (Calibre) |



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Outline of Presentation

- Background introduction
- Machine learning techniques for analog EDA
- Optimization techniques for analog EDA
- Case studies
- Conclusions

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|---|--|---|---|
| | Global Semice | onductor Sales and Gro | owth in 2021,2022 |
| Analog segment had the largest growth | | Growth Rate | Sales (billion) |
| different economic conditions | Analog | 33.1%, 20.3% | 74.0, 89.0 |
| Big demand for analog chips | Logic | 30.8%, 13.7% | 154.8, 176.0 |
| Less cyclical than logic and memory | Memory | 30.9%, -15.4% | 153.8, 130.0 |
| Analog design productivity lags behind digital design by orders of magnitude | Devices / IC (black curves, blue c 10 ¹² 10 ¹¹ 10 ¹⁰ | Analog design has becom bottleneck in the design of of the art microelectro | Devices / person-year (red cr f state- nics |





















Interests in Analog EDA

 Papers with keyword of 'analog circuit design automation' increasing with time

Number of IEEE Papers with keyword 'analog circuit design automation'



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<text><list-item> Statistical Learning Algorithms statistical algorithms are predecessors of learning algorithms Algorithms widely utilized in EDA for decades: Linear regression models Gaussian process models K-nearest neighbors Support vector machines Tree-based models





Statistical Learning Algorithms Statistical algorithms are predecessors of learning algorithms Algorithms widely utilized in EDA for decades: Linear regression models Gaussian process models K-nearest neighbors Support vector machines Tree-based models



Statistical Learning Algorithms Statistical algorithms are predecessors of learning algorithms Algorithms widely utilized in EDA for decades: Linear regression models Gaussian process models K-nearest neighbors Support vector machines Tree-based models

Tree-based Models

Decision tree

• Trained by maximizing information gain $\sum_{i=p} -p * \log_2 p_i$, where p is the probability of class i

Ensemble of trees

- > Reduce overfitting resulting from a single tree
- Random forest
 - $\,{\scriptstyle \succ}\,$ For classification, return the class voted by most trees in ensemble
 - › For regression, take the mean of predictions of all trees in ensemble
- Gradient boost
 - > Usually provides highest accuracy among tree-based models

Advantages:

- Data pre-processing not required
- Fewer data required than neural networks
- > Interpretable tree structure provides additional design information
- Allows ranking of feature importance

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Artificial Neural Networks (ANNs)

- > Fundamental reason for success of AI in the recent decade:
 - > Boost in algorithmic power: novel algorithms based on generalized neural network architecture
 - > Boost in computing power (which again benefits from the development of IC, EDA)
- Deep neural networks
 - > Depth is determined based on problem complexity and dataset size
 - Layers represent different levels of abstraction

| Model Name | $n_{\rm params}$ | $n_{\rm layers}$ | $d_{ m model}$ | $n_{\rm heads}$ | $d_{ m head}$ | Batch Size | Learning Rate |
|-----------------------|------------------|------------------|----------------|-----------------|---------------|------------|----------------------|
| GPT-3 Small | 125M | 12 | 768 | 12 | 64 | 0.5M | 6.0×10^{-4} |
| GPT-3 Medium | 350M | 24 | 1024 | 16 | 64 | 0.5M | $3.0 	imes 10^{-4}$ |
| GPT-3 Large | 760M | 24 | 1536 | 16 | 96 | 0.5M | $2.5 	imes 10^{-4}$ |
| GPT-3 XL | 1.3B | 24 | 2048 | 24 | 128 | 1 M | $2.0 	imes 10^{-4}$ |
| GPT-3 2.7B | 2.7B | 32 | 2560 | 32 | 80 | 1 M | $1.6 	imes 10^{-4}$ |
| GPT-3 6.7B | 6.7B | 32 | 4096 | 32 | 128 | 2M | $1.2 	imes 10^{-4}$ |
| GPT-3 13B | 13.0B | 40 | 5140 | 40 | 128 | 2M | $1.0 	imes 10^{-4}$ |
| GPT-3 175B or "GPT-3" | 175.0B | 96 | 12288 | 96 | 128 | 3.2M | $0.6 	imes 10^{-4}$ |






































































- Population-Based
- Fitness-Oriented
- A fitness parameter to represent the quality of a solutionVariation-Driven
 - Crossover and mutation generates variants randomly
- Broad categories
 - Genetic algorithm
 - Particle swarm
 - Differential evolution
- ▶ ...



Population

Fitness Evaluation

Parent Selection

Crossover and Mutation

Offspring (Next-Generation Solutions)





Simulated Annealing

- > A global optimization technique by approximation
- Preferred when search space is discrete
- > Parameter: a temperature value that keeps decreasing
- temperature=initial temperature/(iteration+1)
- Steps:
 - \blacktriangleright Randomly initialize design variables and evaluate function value f_{old}
 - Sample again in the neighboring region and evaluate function value f_{new}
 - Action:
 - If function value improves, accept
 - If function value worsens, accept with probability $e^{-(f_{new}-f_{old})/temperature}$
- Advantage:
 - > Reduces chance of getting stuck at local optimum since worse candidates are accepted with certain probability

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| Comparison of C | Optimization A | lgorithms fo | or Analog ED. | A | 93 |
|------------------------|------------------|--------------------------|--------------------------|--|----------------------------|
| | Derivative-free? | Guarantee optimality? | Computational complexity | Allow prior knowledge (of distribution) ? | Tradeoff considerations |
| Gradient-based | No | Yes | Low | No | Yes |
| Evolution-based | Yes | No | Medium | No | Yes |
| Bayesian optimization | Yes | No | High | Yes | Yes |
| Reinforcement learning | Yes | No | High | Possibly | Not well formulated |
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Graph Partitioning

- Objective of partitioning for digital physical design: minimize cut edges while balancing for partition sizes
- > Divide and conquer: place and route each partition separately before integration



- > Objective of partitioning of analog circuits before layout: identify circuit hierarchies
 - Grouping utilized as constraints for placement and routing
 - Example: match for symmetry
 - > Algorithms therefore differ from digital partitioning
 - Subgraph isomorphism

Reference: A. B. Kahng, J. Lienig, I. L. Markov, and J. Hu, "VLSI Physical Design: From Graph Partitioning to Timing Closure," Springer, 2011





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Case studies

- > Case study 1: component sizing of analog ICs
- > Case study 2: automated placement and routing
- Case study 3: prediction of interconnect impedance
- Case study 4: transfer learning for design migration
- Conclusions

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VCALT: Variation-aware Classification with Adaptive Labeling Thresholds for Analog Sizing

- > Apply classification to predict whether a candidate solution satisfies the specification
- > To address class imbalance: adaptively set the labeling thresholds
 - With an initial dataset,
 - If the design specification is a lower bound:
 - \cdot labeling threshold = min (design specification, ϵ percentile of the target metric in dataset)
 - If the design specification is an upper bound:
 - \triangleright labeling threshold = max (design specification, (100- ϵ) percentile of the target metric in dataset)

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| _ | | Knowledge-based sizing | Optimization-based sizing |
|-------|----------------------------|--------------------------|---------------------------|
| | | Throwied Se Suscu Sizing | optimization based sizing |
| | Execution | Fast | Slow |
| М | anual effort required | High | Low |
| | Technology scaling | Requires update | Don't care |
| Optin | nality of design solutions | Sub-optimal | Optimal |
| | | | |

Outline of Presentation

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Machine learning techniques for analog EDA

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Conclusions

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GCN-based Approach for Symmetry Detection in Analog Circuits

- Algorithm: GCN trained on bipartite circuit graph
- > Symmetry is identified at primitive cell level, block level and system level
- Limitation 1: hierarchical information of blocks are often directly available from the netlist
- Limitation 2: training data required for each circuit type

| en | ı state-of-ar | t analog synth | iesis platfor | ms require p | re-defined p | rocedural rul | es |
|----|---------------|--|------------------|--------------------------------------|---------------------------------------|--------------------------------------|---------------------|
| | | Programming Language | Open- source? | Performs hierarchy recognition | Automated constraint generation | Technology dependency | Silicon- proven? |
| | BAG | python | Yes | No | No | Independent | No |
| | ALIGN | python, C | Yes | Yes | Yes | Requires compatible tech files | Yes |
| | MAGICAL | Computation: C++, User interface and control: python | Yes | Yes | Yes | Requires compatible tech files | Yes |

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| Error Range | Layout w/o parasitics | Designer's Estimation | Prediction w/ XGB | Prediction w ParaGraph |
|-----------------------|--------------------------|--------------------------|----------------------|---------------------------|
| < 10% | 4 | 6 | 17 | 44 |
| 10%-20% | 0 | 17 | 14 | 10 |
| 20%-30% | 5 | 18 | 4 | 8 |
| 30%-40% | 35 | 2 | 7 | 4 |
| 40%-50% | 14 | 6 | 9 | 1 |
| > 50% | 9 | 18 | 16 | 0 |
| Mean | 37.75% | >100% | 32.14% | 9.60% |
| Geometric Mean | 29.01% | 43.57% | 15.46% | 4.00% |

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Transfer Performance Modeling by Applying GNN and Transfer Learning

- > Train GNN for three amplifier topologies, test on the fourth topology
- Zero-shot learning: GNNs provide coarse estimates of the circuit performance
 GNNs result in less test errors than the baseline ANNs for 14 of the 20 cases
- Few-shot learning: fine-tuned GNNs with transfer learning provide an average reduction of 70.6% in test error (RMSE) as compared to ANN models

| | Two-stage as Test | Three-stage as Test | Folded as Test | Telescopic as Test |
|-----------|-------------------|---------------------|----------------|--------------------|
| Power | -83% / -88% | +300% / -75% | +47% / -10% | +449% / -94% |
| Gain | -48% / -77% | +29% / -61% | -21% / -66% | -19% / -78% |
| Slew Rate | -62% / -74% | -80% / -82% | -97% / -99% | -98% / -99% |
| CMRR | -50% / -70% | -55% / -61% | -43% / -60% | -78% / -81% |
| PSRR | -15% / -67% | +59% / -39% | +33% / -60% | -67% / -71% |

* Scenario I / Scenario 2



Reference: Z. Wu and I. Savidis, "Transfer of Performance Models Across Analog Circuit Topologies with Graph Neural Networks," Proceedings of the ACM/IEEE Workshop on Machine Learning for CAD, pp. 159-165, 2022



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Future Directions

- Improve reliability, robustness, and interpretability of ML models for analog EDA
 More mature and standardized flow of analog synthesis
- > Strong AI for analog synthesis
 - > Current ML models identify correlation instead of causality among data
 - > Learning causality requires expert knowledge
 - Ideal if AI understands human design thinking while discovering new rules for the synthesis of analog circuits
- Meta-learning
 - Learning what to learn
 - > Learn parameter values for base (pre-trained) models for circuit tasks
 - > Learning which model to learn
 - › Auto select the ML and optimization algorithms best suited for a given circuit task
 - Learning how to learn
 - Auto hyperparameter tuning of ML models and generation of pipeline for analog EDA
 Parsing of standard circuit files (SPICE, DSPF, LEF, DEF...)

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Summary of AI-driven Analog EDA

- > ML is applied to improve, not replace heuristics in analog synthesis flow
 - > Heuristics with procedural synthesis still dominate latest analog EDA tools
- Benefits brought by ML for analog EDA:
 - > Reduced simulations required, reduced turnaround time
 - Design space exploration
 - Prediction of parasitic impedances, reliability and variability
 - > Guide optimization or direct generation of schematic and layout design
 - Migration and reuse of past designs
- Requirement on ML-based circuit models:
 - Sample efficiency
 - Generalization
 - Transferability
- > Optimization is backbone of automated analog design flow
- > Need to handle higher device count and more restrictive design rules

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